

1 P Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 13907-062001	Application No. 10/747,663
DEC 21 2004 U.S. PATENT AND TRADEMARK OFFICE (37 CFR §1.98(b))		Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Wolfgang Kalthoff et al.	
				Filing Date December 30, 2003	Group Art Unit 2133

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
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SAC	AQ	WO 02/25471	03-2002	WIPO	—	—		
SAC	AR	WO 02/25500	03-2002	WIPO	—	—		
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**Other Documents (include Author, Title, Date, and Place of Publication)**

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SAC	AT	Haerder T. et al., "Integritätskontrolle," Datenbanken Konzepte und Techniken Der Implementierung, 1999, pp. 397-405, XP002294581 [translation provided]
Examiner Signature 		Date Considered 8-7-06

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.